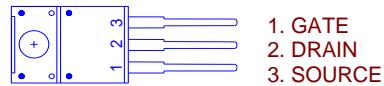
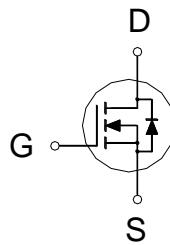


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
**P0770ETF:TO-220F
P0770ETFS:TO-220FS
Halogen-Free & Lead-Free**
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
700V	1.4Ω	7A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	700	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	7	A
		4	
Pulsed Drain Current ¹	I_{DM}	20	A
Avalanche Current ³	I_{AS}	2.2	
Avalanche Energy ³	E_{AS}	24	mJ
Power Dissipation	P_D	43	W
		17	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.9	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.²Ensure that the channel temperature does not exceed 150°C.³ $V_{DD} = 50V$, $L = 10mH$, starting $T_J = 25^\circ C$.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	700			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	2.6	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 700V, V_{GS} = 0V, T_C = 25^\circ C$			1	μA
		$V_{DS} = 560V, V_{GS} = 0V, T_C = 100^\circ C$			10	

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 3.5A$		1.1	1.4	Ω
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 3.5A$		9		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		1185		pF
Output Capacitance	C_{oss}			105		
Reverse Transfer Capacitance	C_{rss}			10		
Total Gate Charge ²	Q_g	$V_{DD} = 560V, I_D = 7A, V_{GS} = 10V$		30		nC
Gate-Source Charge ²	Q_{gs}			5		
Gate-Drain Charge ²	Q_{gd}			9		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 350V, I_D = 7A, R_G = 25\Omega$		35		nS
Rise Time ²	t_r			75		
Turn-Off Delay Time ²	$t_{d(off)}$			80		
Fall Time ²	t_f			57		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S				7	A
Forward Voltage ¹	V_{SD}	$I_F = 7A, V_{GS} = 0V$			1	V
Reverse Recovery Time	t_{rr}	$I_F = 7A, dI_F/dt = 100A/\mu S$		404		nS
Reverse Recovery Charge	Q_{rr}			3.8		uC

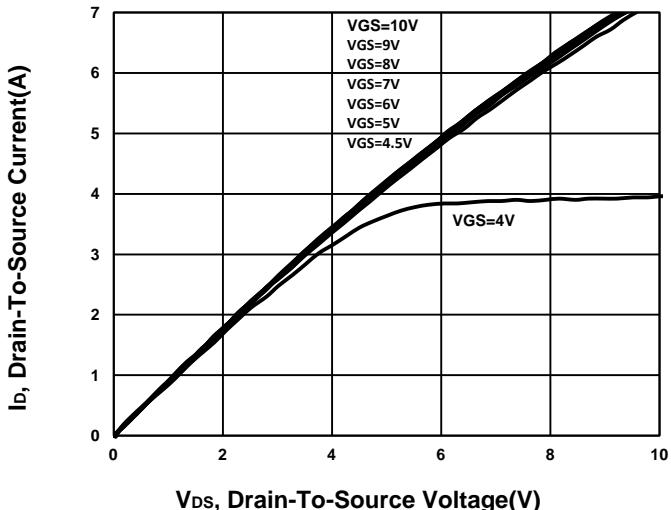
¹Pulse test : Pulse Width $\leq 380 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

NIKO-SEM

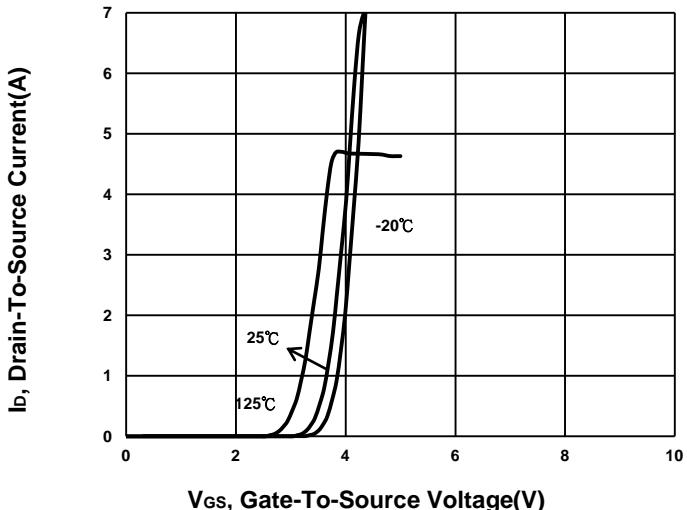
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P0770ETFS:TO-220FS
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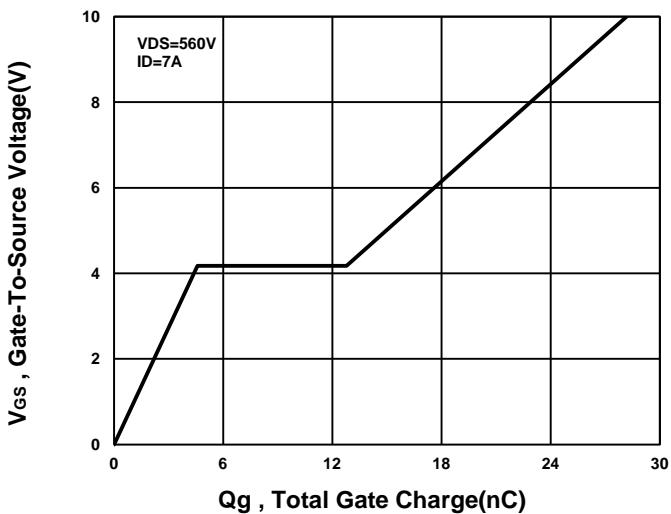
Output Characteristics



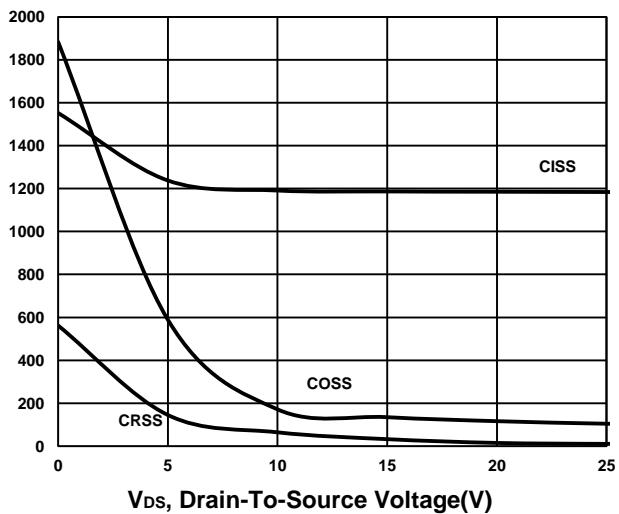
Transfer Characteristics



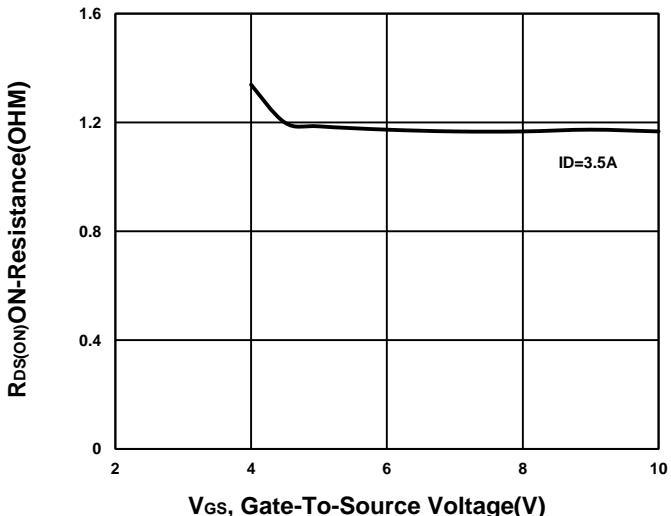
Gate charge Characteristics



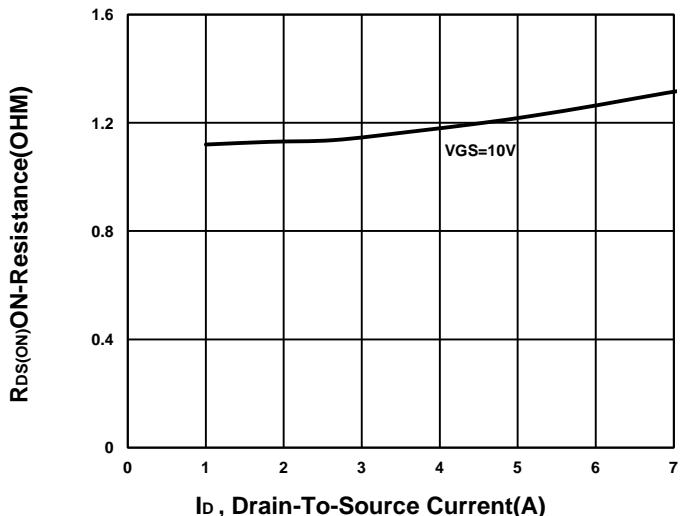
Capacitance Characteristic



On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current

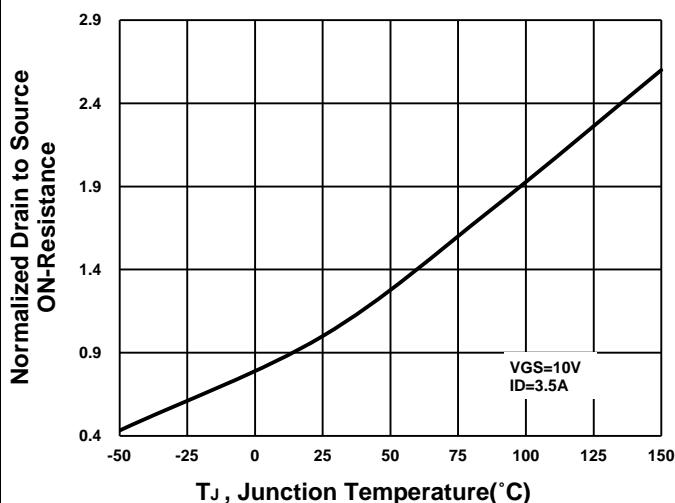


NIKO-SEM

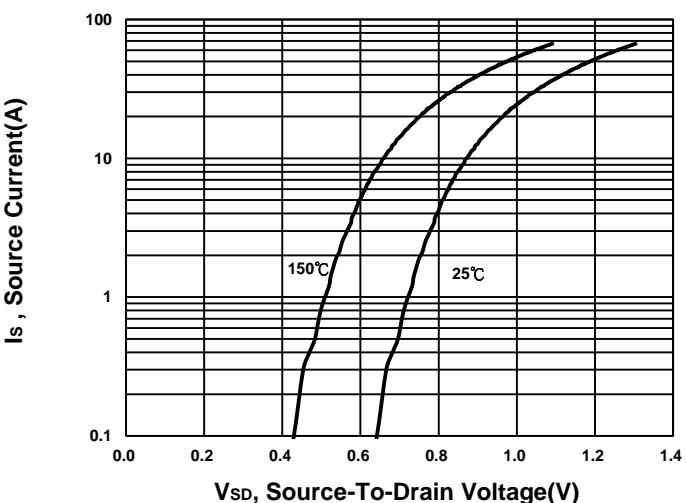
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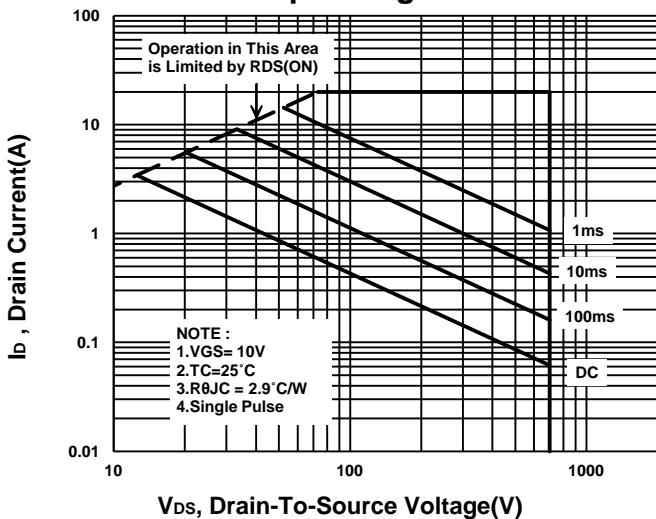
On-Resistance VS Temperature



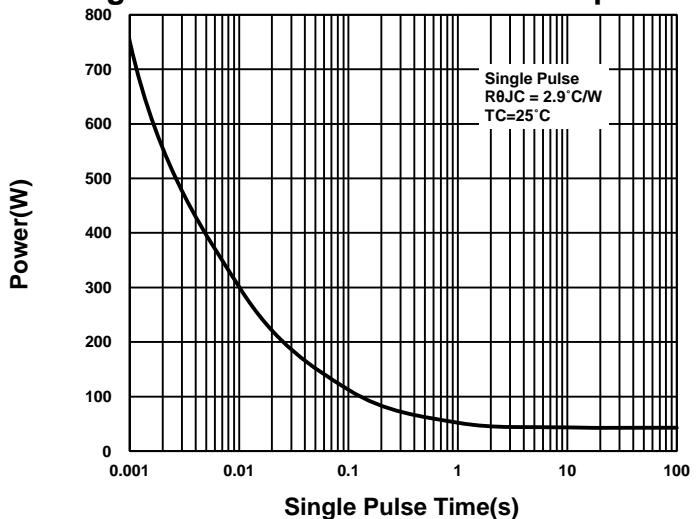
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

